

**Notice of References Cited**

Application/Control No.

10/561,680

Applicant(s)/Patent Under

Reexamination

OHNO ET AL.

Examiner

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Art Unit

1796

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-7,135,518 B2	11-2006	Bandou et al.	524/445
B	US-			
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K	US-			
L	US-			
M	US-			

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**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Abstract in English; Nakagawa et al; 05-2000.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
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